

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/622,351	LEE, JOON HYEON	
Examiner Stanetta D. Isaac		Art Unit 2812	Page 1 of 1	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,228,727	05-2001	Lim et al.	438/296
	B	US-6,165,870	12-2000	Shim et al.	438/424
	C	US-6,001,707	12-1999	Lin et al.	438/433
	D	US-6,562,696	05-2003	Hsu et al.	438/424
	E	US-5,904,538	05-1999	Son et al.	438/424
	F	US-5,801,083	09-1998	Yu et al.	438/424
	G	US-6,569,750	05-2003	Kim et al.	438/524
	H	US-6,437,417	08-2002	Gilton, Terry L.	257/506
	I	US-2003/0045079	03-2003	Han, Chang Hun	438/585
	J	US-6,495,424	12-2002	Kunikiyo, Tatsuya	438/296
	K	US-6,274,500	08-2001	Xuechun et al.	438/706
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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